imall

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832 Email & Skype: info@chipsmall.com Web: www.chipsmall.com Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China



International

IRL2910PbF

PD - 94993

Lead-Free

- Logic-Level Gate Drive
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

Description

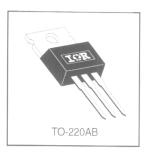
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

Absolute Maximum Ratings

HEXFET® Power MOSFET $V_{DSS} = 100V$ $R_{DS(on)} = 0.026\Omega$ $I_D = 55A$

S



Parameter		Max.	Units	
$I_{D} @ T_{C} = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	55		
$I_D @ T_C = 100^{\circ}C$ Continuous Drain Current, $V_{GS} @ 10V$		39	A	
I _{DM}	Pulsed Drain Current ①	190		
$P_D @T_C = 25^{\circ}C$	Power Dissipation	200	W	
	Linear Derating Factor	1.3	W/°C	
V _{GS}	Gate-to-Source Voltage	± 16	V	
E _{AS}	Single Pulse Avalanche Energy®	520	mJ	
I _{AR}	Avalanche Current@©	29	A	
E _{AR}	Repetitive Avalanche Energy®	20	mJ	
dv/dt	Peak Diode Recovery dv/dt 3	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{0JC}	Junction-to-Case		0.75	°C/W
R _{ecs}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
R _{0JA}	Junction-to-Ambient		62	°C/W

www.irf.com

1

International

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}\!/\!\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I _D = 1mA
				0.026		V _{GS} = 10V, I _D = 29A ④
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.030	Ω	$V_{GS} = 5.0V, I_D = 29A$ (4)
				0.040		$V_{GS} = 4.0V, I_D = 24A$ (4)
V _{GS(th)}	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g _{fs}	Forward Transconductance	28			S	$V_{DS} = 50V, I_D = 29A$
	Drain to Source Lastrana Ormant			25		$V_{DS} = 100V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100		V _{GS} = 16V
1922	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -16V
Qg	Total Gate Charge			140		I _D = 29A
Q _{gs}	Gate-to-Source Charge			20	nC	$V_{\rm DS} = 80V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			81		V _{GS} = 5.0V, See Fig. 6 and 13 ④
t _{d(on)}	Turn-On Delay Time		11			$V_{DD} = 50V$
tr	Rise Time		100			I _D = 29A
t _{d(off)}	Turn-Off Delay Time		49		ns	$R_{G} = 1.4\Omega, V_{GS} = 5.0V$
t _f	Fall Time		55			$R_{D} = 1.7\Omega$, See Fig. 10 @
1	Internal Drain Inductance		4.5			Between lead, o
L _D	internal Drain Inductance		4.5			6mm (0.25in.)
L _S	Internal Source Inductance		7.5		- nH	from package
						and center of die contact
Ciss	Input Capacitance		3700			V _{GS} = 0V
Coss	Output Capacitance		630		рF	$V_{DS} = 25V$
Crss	Reverse Transfer Capacitance		330			f = 1.0MHz, See Fig. 5

Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current					MOSFET symbol
	(Body Diode)			55		showing the
I _{SM}	Pulsed Source Current				integral reverse	
	(Body Diode) ①		190		p-n junction diode.	
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 29A, V_{GS} = 0V$ (4)
t _{rr}	Reverse Recovery Time		240	350	ns	$T_J = 25^{\circ}C, I_F = 29A$
Qrr	Reverse RecoveryCharge		1.8	2.7	μC	di/dt = 100A/µs ④
ton	Forward Turn-On Time	Intr	Intrinsic tum-on time is negligible (tum-on is dominated by $L_{S}+L_{D}$)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

3 I_{SD} \leq 29A, di/dt \leq 490A/µs, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175°C

④ Pulse width \leq 300µs; duty cycle \leq 2%.

International **tor** Rectifier

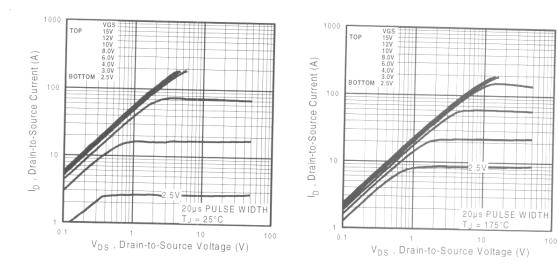


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

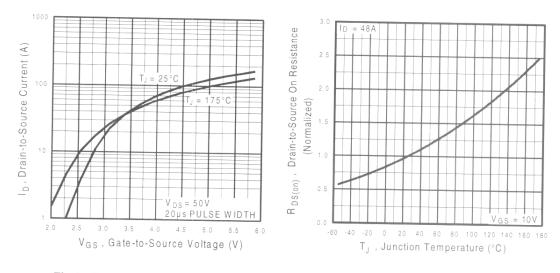
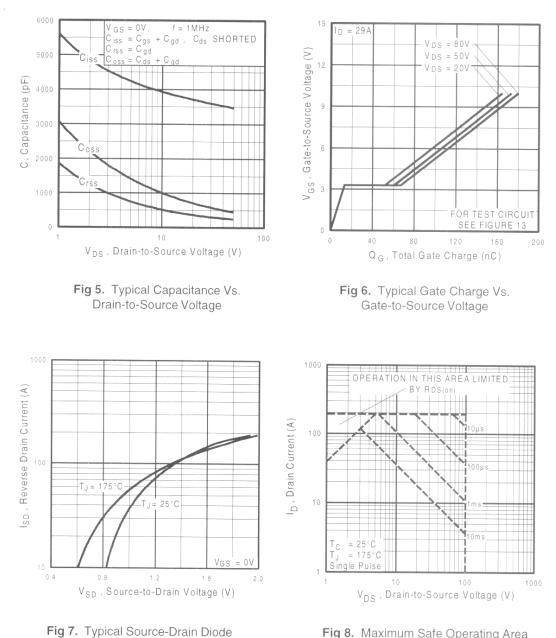


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance Vs. Temperature

International **TOR** Rectifier





www.irf.com

Forward Voltage

International

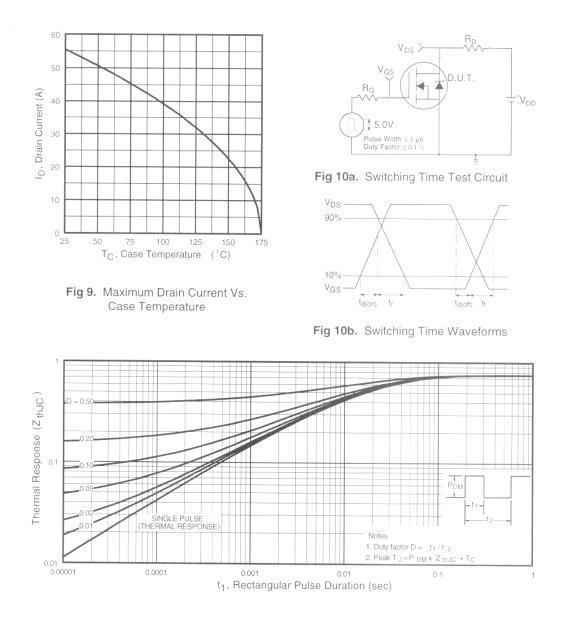


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

International

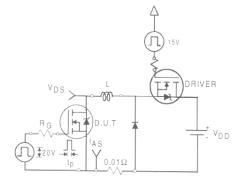


Fig 12a. Unclamped Inductive Test Circuit

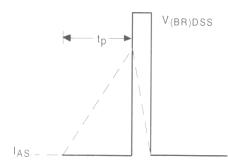


Fig 12b. Unclamped Inductive Waveforms

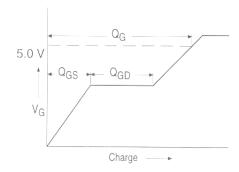


Fig 13a. Basic Gate Charge Waveform

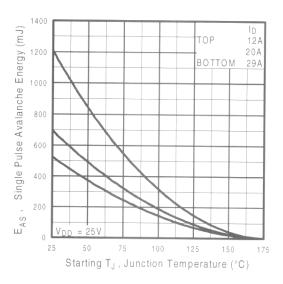


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

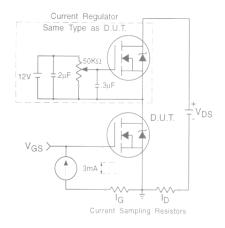
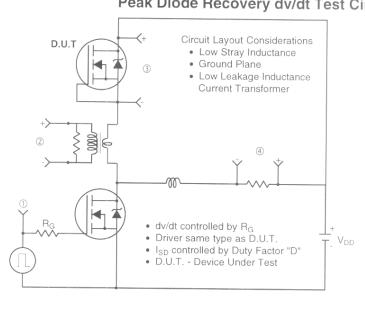
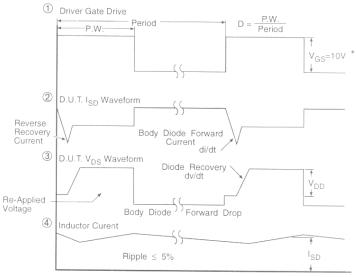


Fig 13b. Gate Charge Test Circuit



Peak Diode Recovery dv/dt Test Circuit



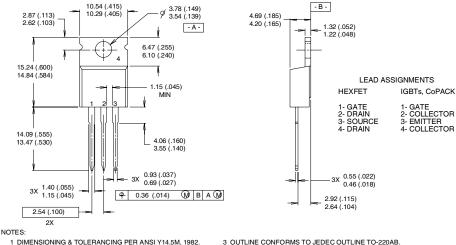
* V_{GS} = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

International

TO-220AB Package Outline

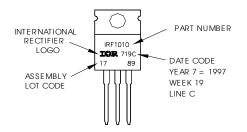
Dimensions are shown in millimeters (inches)



1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982. 2 CONTROLLING DIMENSION : INCH 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB. 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010 LOT CODE 1789 ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C" **Note:** "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.

International

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903 Visit us at www.irf.com for sales contact information.02/04 8 Note: For the most current drawings please refer to the IR website at: <u>http://www.irf.com/package/</u>